

## **LIST OF JOURNAL PAPERS 2024**

1. Solé R., Ferrer C., Aviñó-Salvadó O., Jordà X., Perpiñà X.  
**“Measurement uncertainty in Fourier coefficient-based time series reconstruction considering calibration effects in thermal imaging”**.  
**IEEE Transactions on Instrumentation and Measurement, 1006711, 2024.,**  
**DOI: 10.1109/TIM.2024.3441016**
2. Lopez Paz, I.; Fleta, C.; Rafí, J.M.; Rius, G.; Godignon, P.; Pellegrini, G.; Mena, S.; Jimenez, M.; Henao, A.; Bravo, J.; Boer, R.; Molas, B.; Guardiola, C.  
**“Characterisation of SiC radiation detector technologies with synchrotron X-rays”**  
**Journal of Instrumentation, vol.19, pp. 119 – 127, 2024.**  
**DOI: 10.1088/1748-0221/19/12/P12017**
3. Merino, J.P.; Brosel-Oliu, S.; Rius, G.; Illa, X.; Sulleiro, M.V.; Del Corro, E.; Masvidal-Codina, E.; Bonaccini Calia, A.; Garrido, J.A.; Villa, R.; Guimerà-Brunet, A.; Prato, M.; Criado, A.; Prats-A.  
**“Ethanol Solvation of Polymer Residues in Graphene Solution-Gated Field Effect Transistors”**  
**ACS Sustainable Chemistry and Engineering, vol.12, pp. 9133 – 9143, 2024.**  
**DOI: 10.1021/acssuschemeng.4c01538**
4. Avino-Salvado, O.; Buttay, C.; Bonet, F.; Raynaud, C.; Bevilacqua, P.; Rebollo, J.; Morel, H.; Perpina, X.  
**“Physics-Based Strategies for Fast TDDB Testing and Lifetime Estimation in SiC Power MOSFETs”**  
**IEEE TRANSACTIONS ON INDUSTRIAL ELECTRONICS, vol.71, pp. 5285 – 5295, 2024.**  
**DOI: 10.1109/TIE.2023.3281705**
5. Lopez Paz, I.; Godignon, P.; Moffat, N.; Pellegrini, G.; Rafí, J.M.; Rius, G.  
**“Position-resolved charge collection of silicon carbide detectors with an epitaxially-grown graphene layer”**  
**Scientific Reports, vol. 14, pp. 246 – 249, 2024.**  
**DOI: 10.1038/s41598-024-60535-3**
6. García-Serrano, A.; Cea, P.; Osorio, H.M.; Pérez-Murano, F.; Rius, G.;  
**“Low, P.J.; Martin, S Robust large area molecular junctions based on transparent and flexible elèctrodes”**  
**Journal of Materials Chemistry C, vol. 12, pp. 1325 – 1333, 2024.**  
**DOI: 10.1039/d3tc02237d**
7. Jiménez-Ramos, M.C.; García Osuna, A.; Rodríguez-Ramos, M.; Viezzer, E.; Pellegrini, G.; Godignon, P.; Rafí, J.M.; Rius, G.; García López, J.  
**“Spectrometric performance of SiC radiation detectors at high temperature”**  
**Radiation Physics and Chemistry, vol. 214, 1841, 2024.**  
**DOI: 10.1016/j.radphyschem.2023.111283**

8. Torras-Coloma, A.; Martínez de Olcoz, L.; Céspedes, E.; Bertoldo, E.; López-Núñez, D.; Paul, S.; Wernsdorfer, W.; Rius, G.; Forn-Díaz, P.  
[“Superconducting nitridized-aluminum thin films”](#)  
**Superconductor Science and Technology**, vol. 37, pp. 754 – 757, 2024.  
[DOI: 10.1088/1361-6668/ad20fc](#)